

Wafer ID: 15F3

Start date: 2024-04-13

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There were 8 total error messages in 1 wafer.

Number of scan chain errors: 0

Number of analog scan failures: 0

Number of digital scan failures: 1

Number of VDD errors: 0

Number of chips with dead pixels: 0

Number of DAQ function program terminations: 0

Number of programming errors: 0

Number of DAQ digital scan errors: 1

Number of DAC calibration errors: 0

1 chip(s) did not complete testing (chip ID(s): 67).

Total number of dead pixels: 0 (of 145152 in 1 wafer)

Other errors (3):

- Error while testing chip N61F26-15F3-D8
- Could not communicate with the instruments!
- Bandgap voltage measurement failed!

